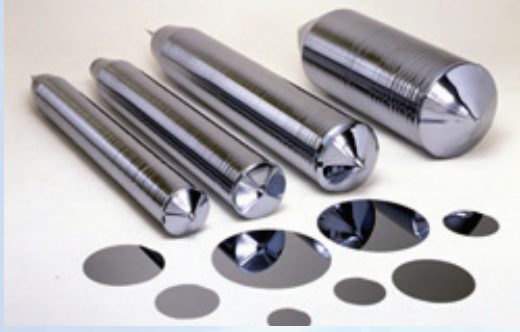
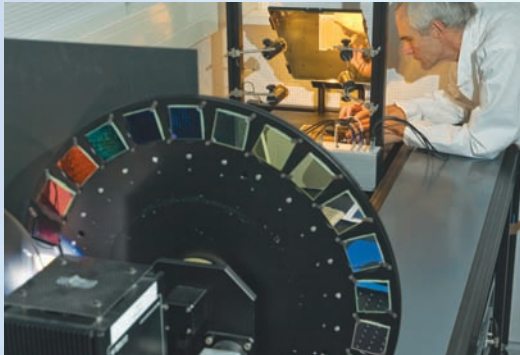


## Characterising solar wafers and cells



### Wafers

- Wafer strength
- Cs, Oi (FTIR)
- Impurity levels
- Minority carrier lifetime & diffusion length ( $\mu$ W-PCD and MFCA)
- Crystal density



### Cells

- I-V (dark, illuminated, reverse, forward, solar simulator)
- Spectral responsivity
- Spectral reflectance and transmission
- Series resistance free I-V
- Metalisation resistance (busbar-to-busbar)
- Defect and resistance imaging (PL, EL)
- Shunt imaging (Thermography)
- Contact resistance mapping (CORESCAN)
- Emitter sheet resistance mapping (SHERESCAN)
- Optical characterization thin-films (Ellipsometry)



### Customers

- Manufacturers of feedstock and ingots
- Wafer suppliers
- Solar cell manufacturers

## Our Expertise - Your Opportunity